

Source	x_-	y_-	x_+	y_+
Statistical	1.7	2.2	1.9	1.9
Strong phase measurements	0.4	1.1	0.4	0.9
Efficiency corrections	0.6	0.2	0.6	0.1
Mass fit PDFs	0.2	0.3	0.2	0.3
Different mis-ID shape over Dalitz plot	0.2	0.1	0.1	0.1
Different low mass shape over Dalitz plot	0.1	0.2	0.1	0.1
Uncertainty on $B_s^0 \rightarrow \bar{D}^0 \pi^+ K^-$ yield	0.1	0.1	0.1	0.1
Bias correction	0.1	0.1	0.1	0.1
Bin migration	0.1	0.1	0.1	0.1
K^0 CP violation and material interaction	0.1	0.2	0.1	0.1
Total experimental systematic uncertainty	0.7	0.5	0.7	0.4